



Welcome to
046188 Winter semester 2012
Mixed Signal Electronic Circuits
Instructor: Dr. M. Moyal

Lecture 12

Parallel ADCs- Time Interleaved ADC

Calibration techniques

www.gigalogchip.com

Agenda



Architectures

Source of Errors

Calibration Methods

Analysis

Design Example

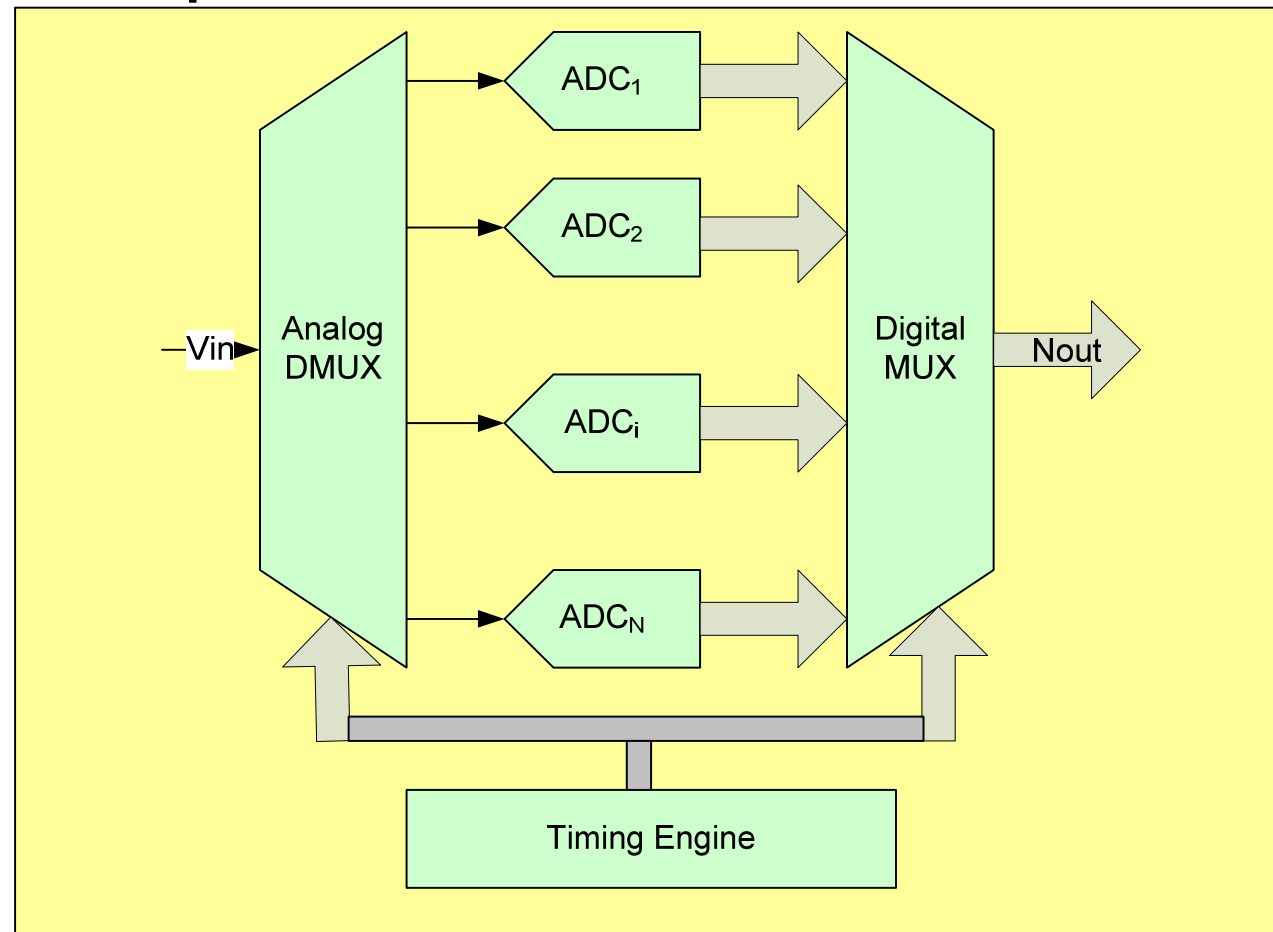


- Time Interleaved ADC Architectures
 - The concept of time interleaving
 - Mismatch Artifacts in Time Interleaved ADC
 - Time Interleaved ADC Examples
- ADC Calibration Techniques
 - The concept of ADC Calibration
 - Limitations of ADC Calibration
 - Classification of Calibration Techniques
 - Examples of ADC Calibration Techniques
 - Trimming Techniques
 - Digital Calibration in Pipeline ADC
 - Digital Calibration with State Space Error Table

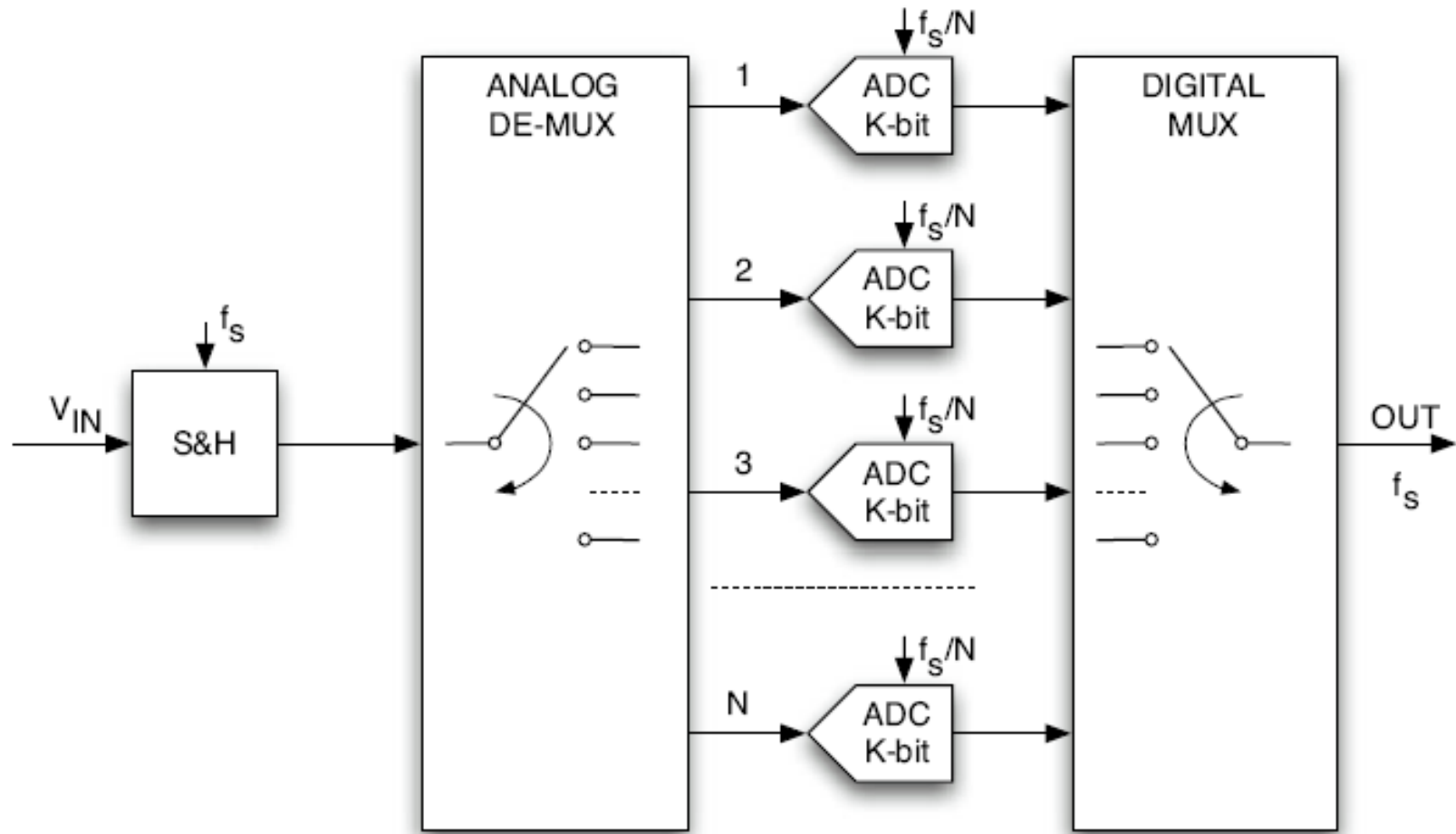
1a. Time Interleaved ADC Approach (1)



- **System Level Concept:**



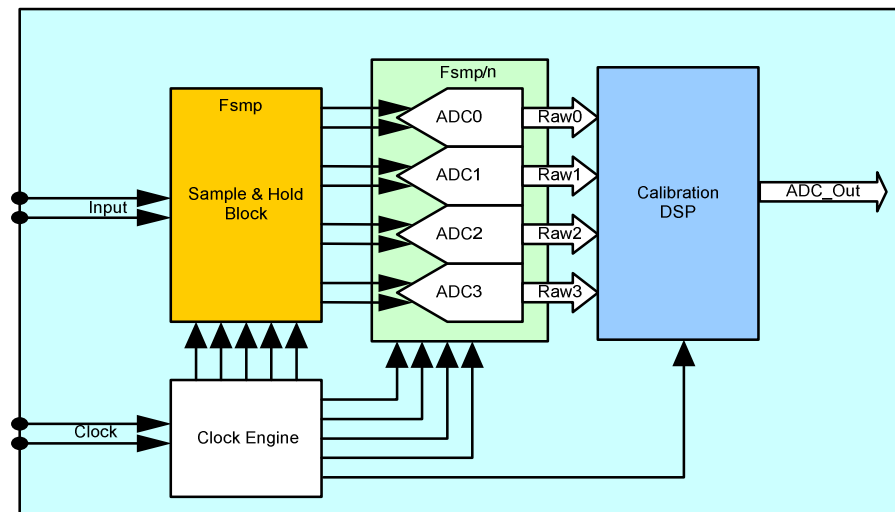
MUXING interface





1a. Time Interleaved ADC Approach (2)

- Partition the problem of building a high resolution ultra-fast ADC to 3 main sub-problems:
 - Build a $n \times$ time-interleaved sample and hold
 - Build n identical ADC-s that each samples at $F_{\text{smp}/n}$
 - Perform digital signal processing to eliminate/reduce interleaving artifacts



HOW TO CHOOSE ? –



Example: in class.

SAR Interleaving ADC

Backward approach:

Given technology

1) design a comparator find its maximum speed- use desired power I_{dd} - call it time: T_1

2) Design best Digital FF (logic) : determine speed T_2

3) Switch time to charge maximum cap MSB T_3

3) $T = T_1 + T_2 + T_3$ this is roughly maximum one cycle

clock speed is T , need number of bit +1 Time per ADC.

2x BW needed

1b. Mismatch Artifacts due to Time Interleaved Architecture (1)

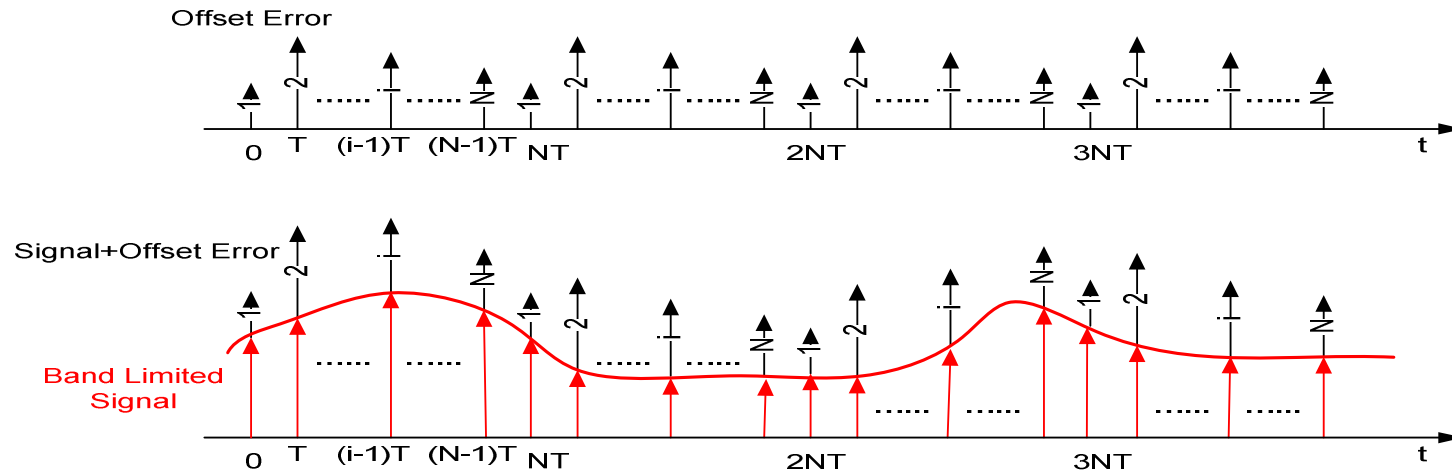


- The branches of a time interleaved ADC are not identical
- There are 3 main mismatch issues:
 - Offset mismatch
 - Gain mismatch
 - Timing instance skew
 - can be overcome if full speed sample and hold is used
 - Can be corrected in DSP – generalization of Nyquist theorem for non-uniform sampling

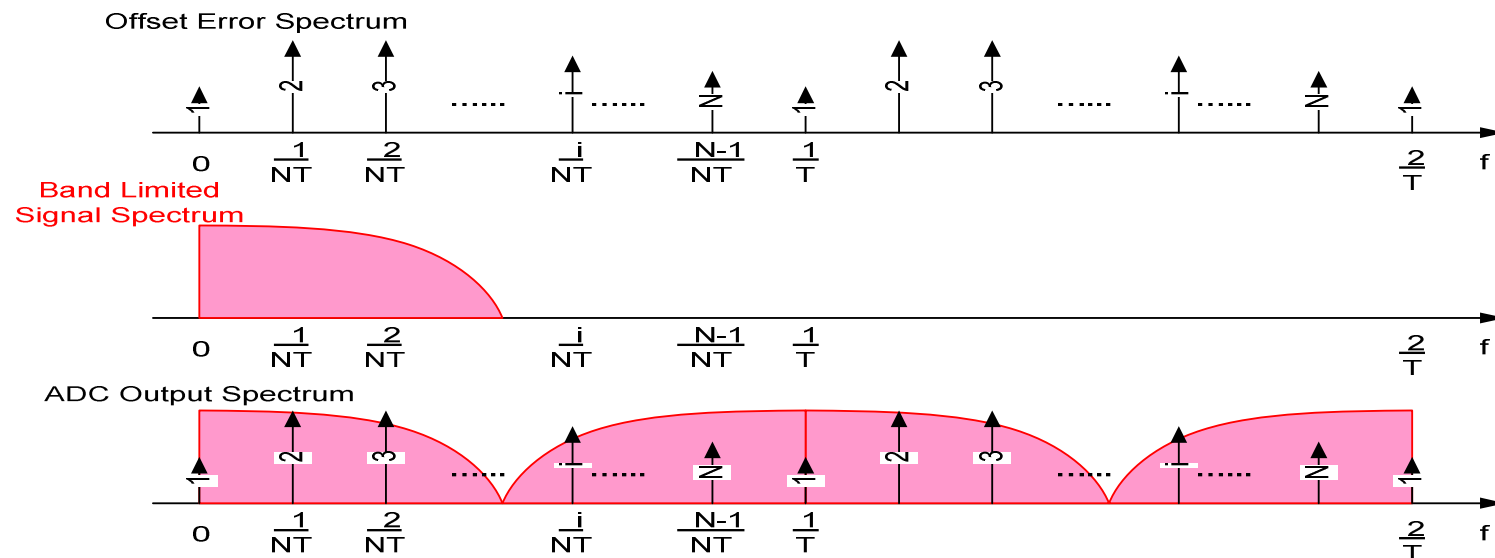
1b. Mismatch Artifacts due to Time Interleaved Architecture (2 - Offset)



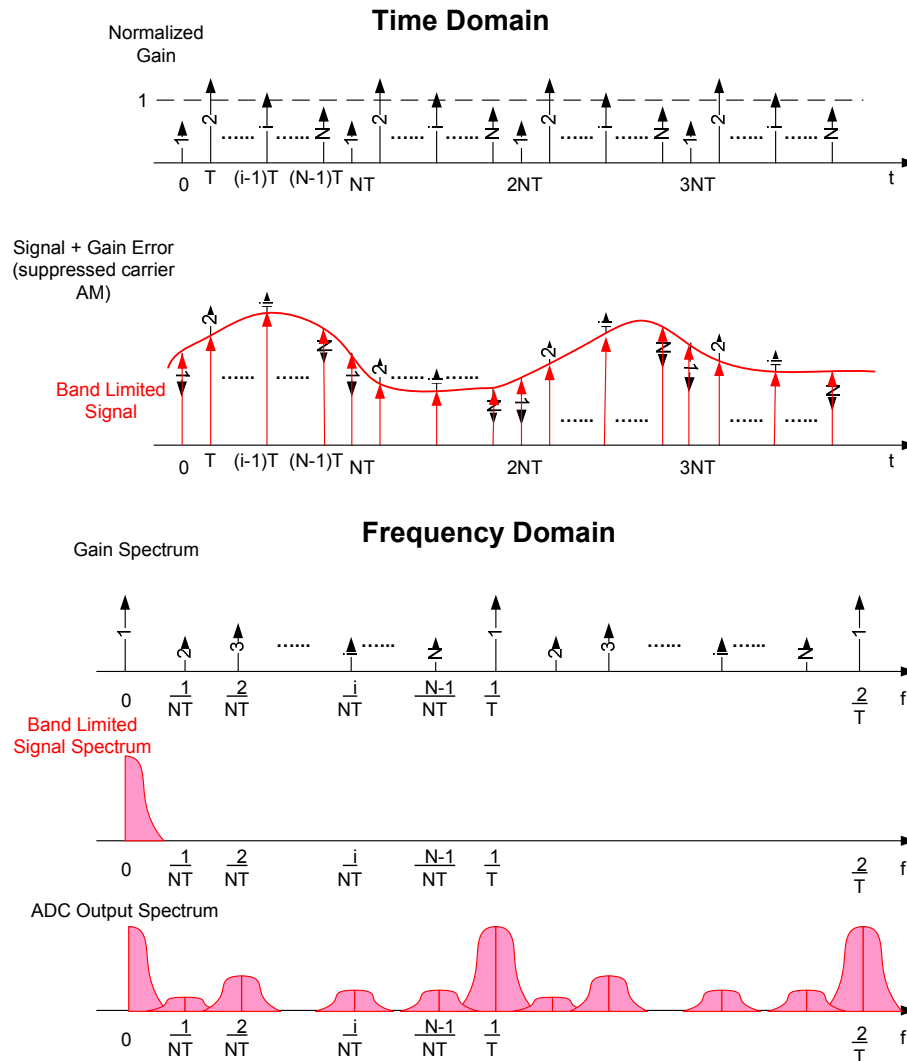
Time Domain



Frequency Domain



1b. Mismatch Artifacts due to Time Interleaved Architecture (3 - Gain)

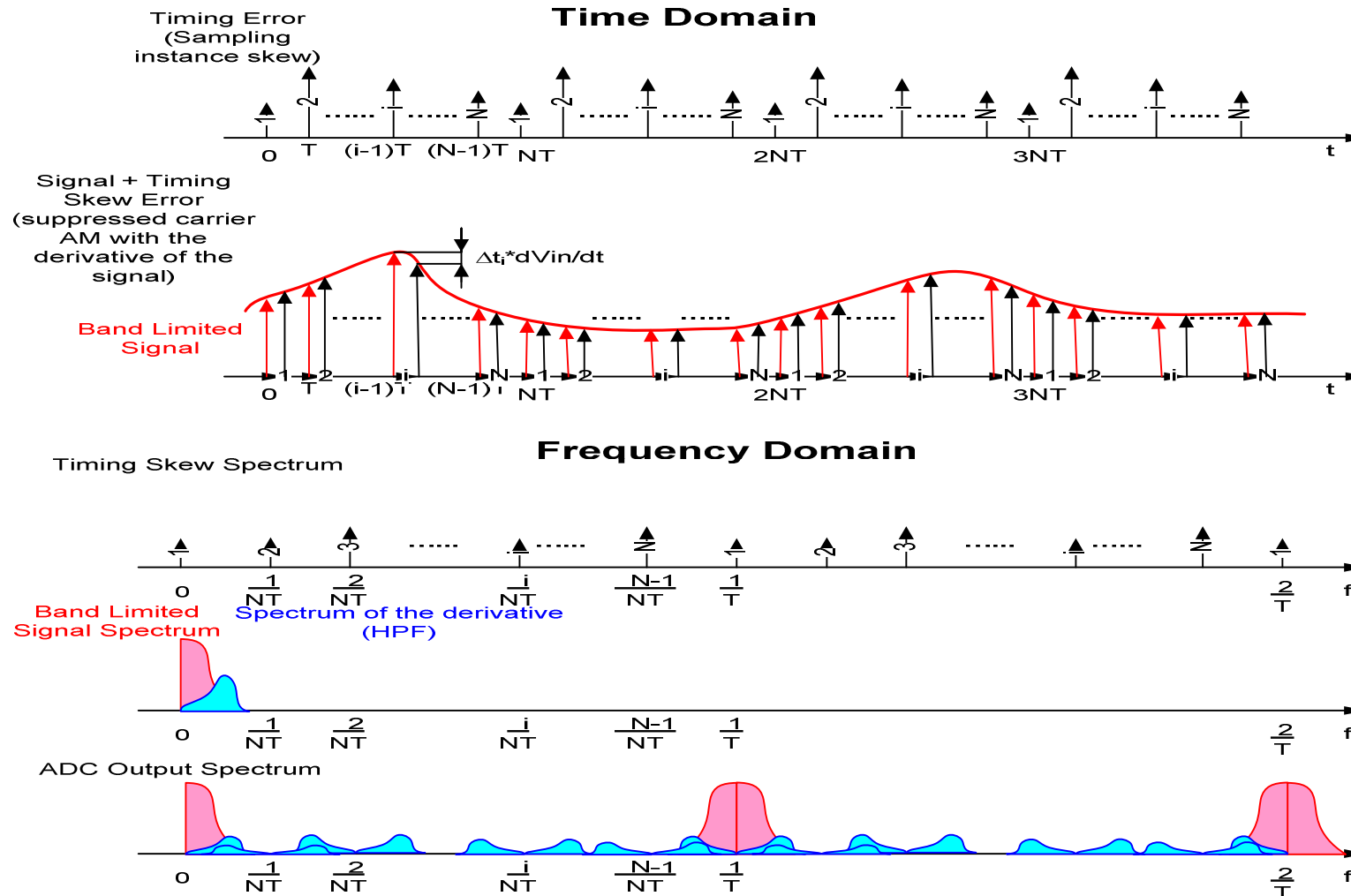


Analytical Formulas:

N. Kurosawa, K. Maruyama, H. Kobayashi, H. Sugawara, K. Kobayashi
 , "Explicit Formula for Channel Mismatch Effects in Time-Interleaved ADC Systems", IEEE Transactions on Circuits and Systems I: Fundamental Theory and Applications, Volume: 48 , Issue: 3 , March 2001,
 Pages:261 – 271

$$SNR_{Missmatch} = -10 \cdot \log \left(\sigma_{\Delta G}^2 + \frac{8 \cdot \sigma_{Noff}^2}{N_{FS}^2} \right)$$

1b. Mismatch Artifacts due to Time Interleaved Architecture (4 Timing Skew)





Five Important Sources of Mismatch

- Offset mismatch
- Gain Mismatch
- Clock Skew
- Bandwidth Mismatch
 - Make sure that BW is wide enough
- Jitter
 - Use a low-jitter source

KEY DEPENDENCIES



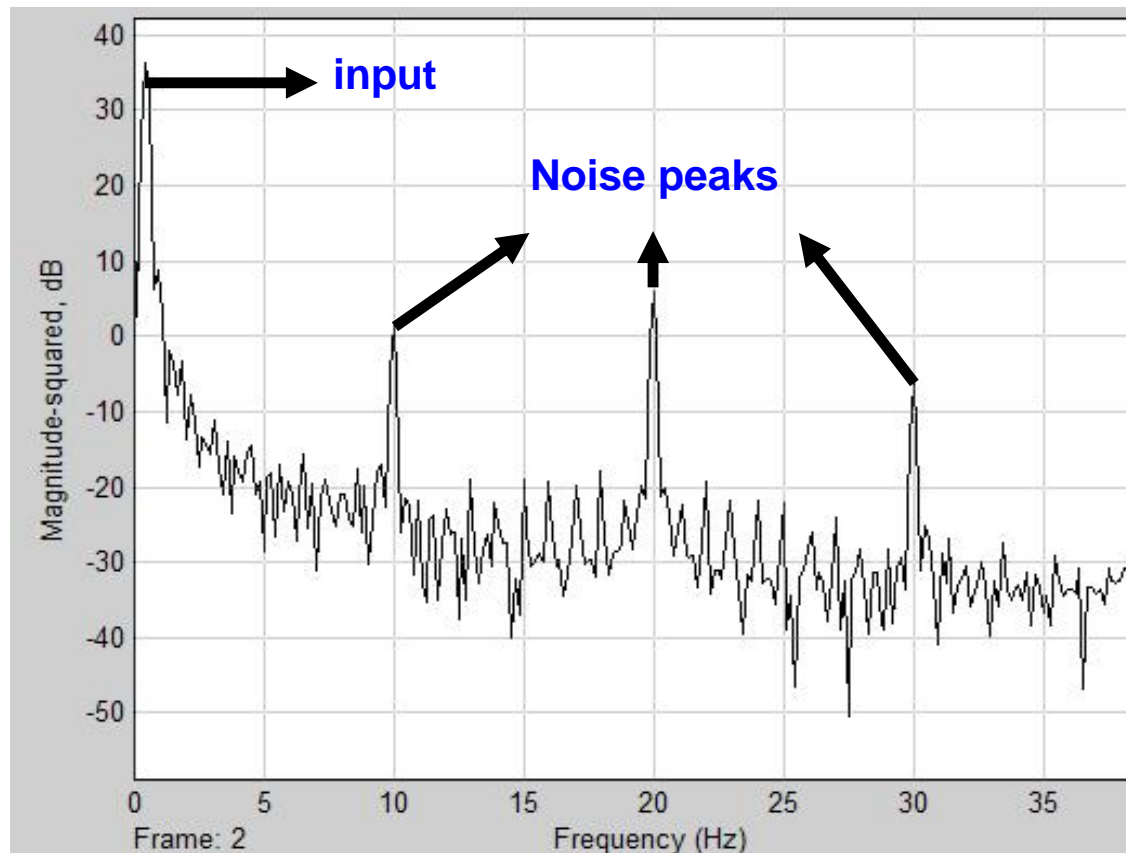
	SNR Degradation Due To			
	Offset	Gain	Clock skew	BW
Input amplitude	independent	Linearly dependent	Linearly dependent	Nonlinearly dependent
Input frequency	independent	independent	Linearly dependent	Nonlinearly dependent



$$\begin{aligned}in &= \cos(\omega_0 t + \theta) \\ out1 &= \cos(\omega_0 n T_s + \theta) + V_{os1} \\ out2 &= \cos(\omega_0 n T_s + \theta) + V_{os2}\end{aligned}$$

.....

- Input amplitude and frequency independent
- Causes fixed pattern noise
- Noise peaks at frequencies, $f = k \cdot F_s / M$
- **M=# of interleaved ADCs**
 - F_s =sample frequency
 - $k=1, 2, 3, \dots M-1$
 - Noise peak amplitudes are offset voltage dependent



Spectrum of a 4-channel interleaved ADC model

$F_{in}=0.5\text{Hz}$, $F_s=40\text{Hz}$

Noise peaks at 10Hz, 20Hz, 30Hz

Gain Mismatch Problem



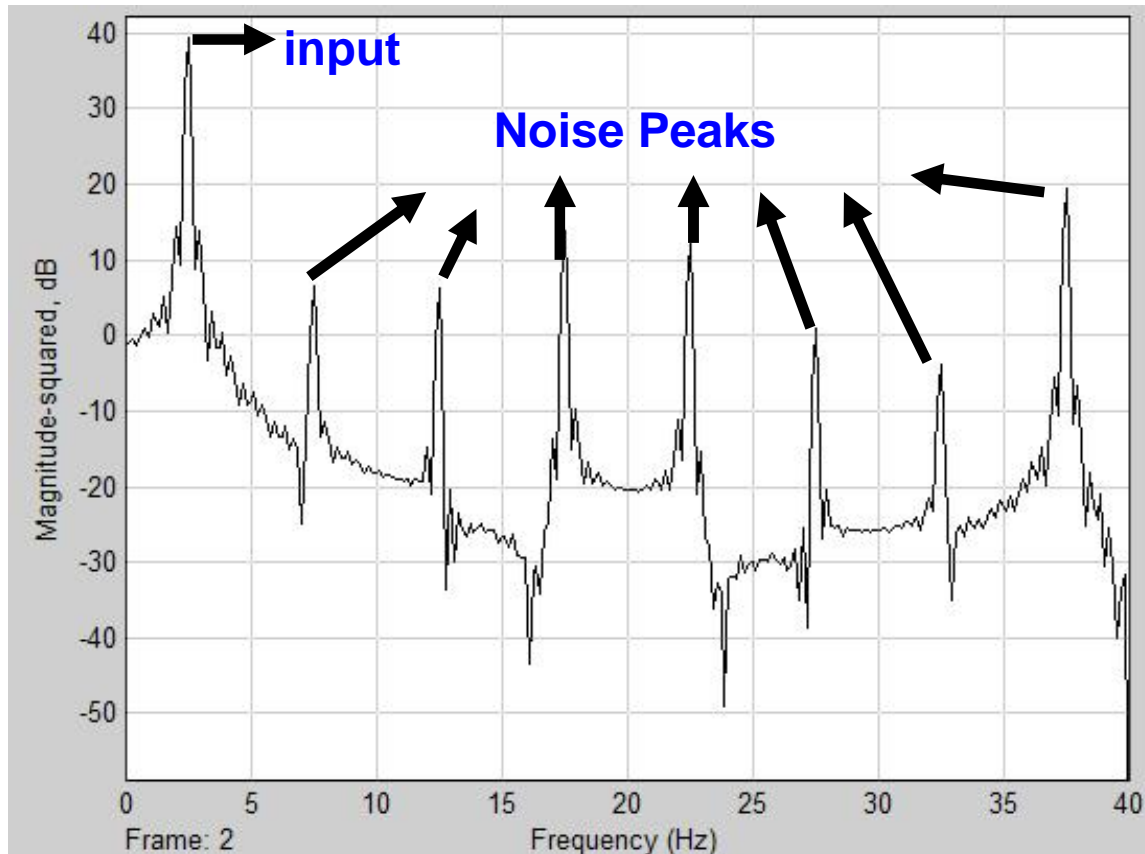
$$\mathbf{in = \cos(\omega_0 t + \theta)}$$

$$\mathbf{out1 = G1 * \cos(\omega_0 n T_s + \theta)}$$

$$\mathbf{out2 = G2 * \cos(\omega_0 n T_s + \theta)}$$

- Error is max and min when the input is max and min, respectively
- Linear input amplitude dependency
- Input frequency independent
- Noise peaks at frequencies, $f = \pm f_{in} + k * F_s / M$
 - f_{in} = input frequency
 - M = # of interleaved ADCs
 - F_s = sample frequency
 - $k = 1, 2, 3, \dots, M-1$

Gain Mismatch Problem



Spectrum of a 4-channel interleaved ADC mode

$F_{in}=2.5\text{Hz}$, $F_s=40\text{Hz}$

Noise peaks at 7.5Hz, 12.5Hz, 17.5Hz, 22.5Hz....

Timing Mismatch Problem



$$in = \cos(\omega_0 t + \theta)$$

$$out1 = \cos(\omega_0 n_1 T_s + \theta)$$

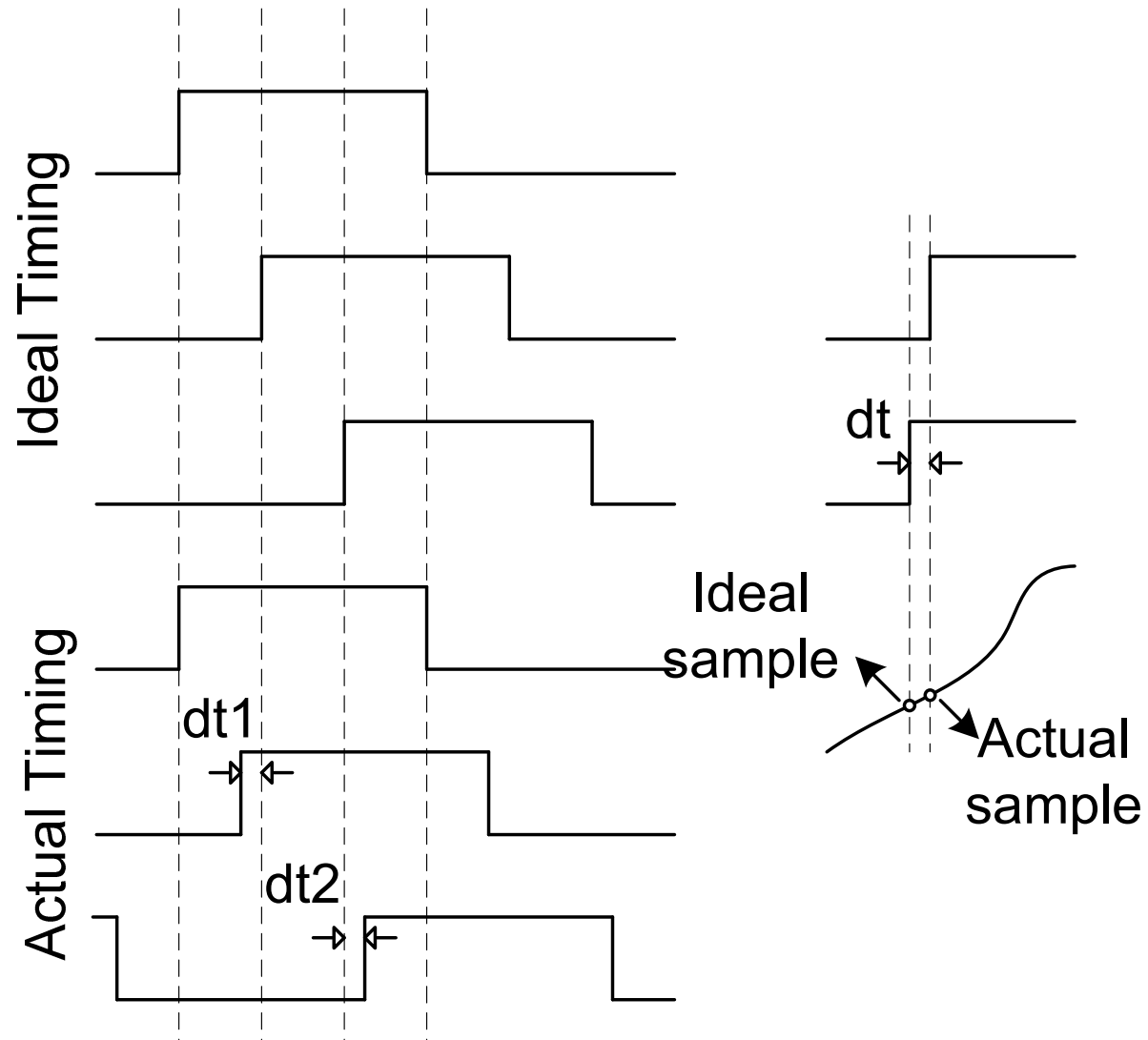
$$out2 = \cos(\omega_0 (n_2 T_s + dT) + \theta)$$

.....

- Creates nonuniform sampling
- Error is max. when the input slope is max, thus frequency dependent
- Linear input amplitude dependency

- Noise peaks are at the same frequencies as gain offset
- Noise peaks at frequencies, $f = \pm f_{in} + k \cdot F_s / M$
 - f_{in} = input frequency
 - M = # of interleaved ADCs
 - F_s = sample frequency
 - $k = 1, 2, 3, \dots, M-1$

Timing Mismatch Problem



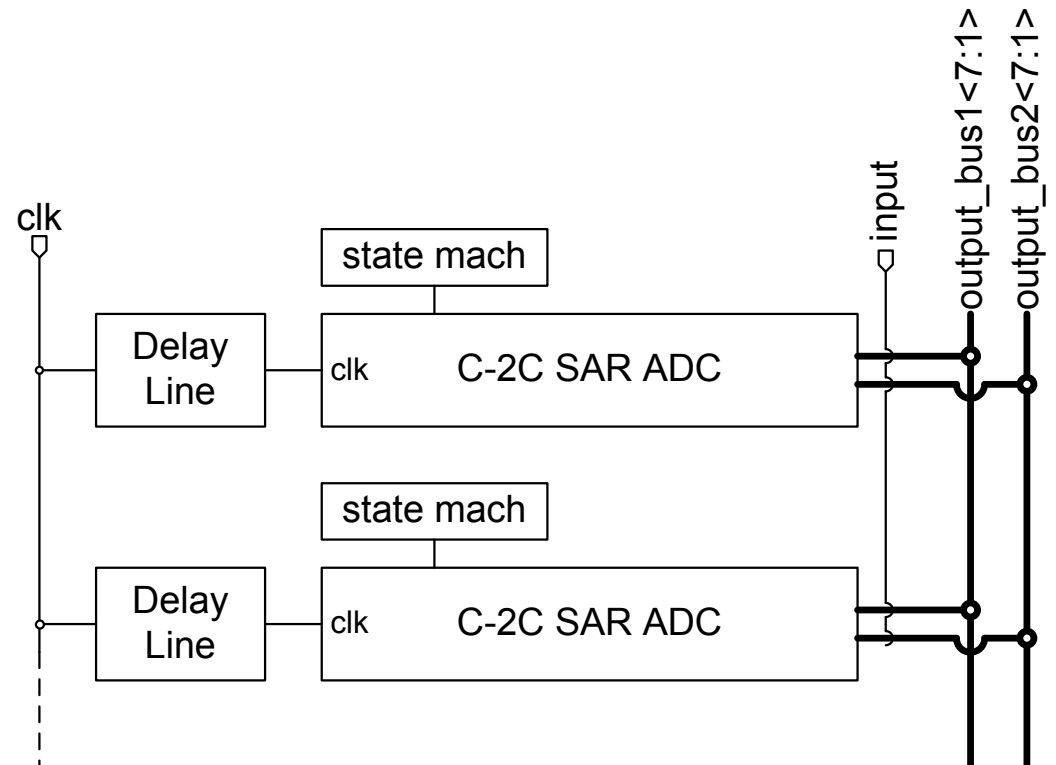


CALIBRATIONS



: Timing Calibration-1

- This has to be done, after the gain and the offset calibration
- Take the outputs of the two consecutive ADCs
- Take the difference between the samples
- Take the standard deviation of the difference after adequate number of samples are collected



2b. Limitations of ADC Calibration Techniques



- Calibration techniques can not cancel:
 - Random effects (thermal noise, jitter)
 - Quantization noise (an 8 bit ADC can not become 9 bit after calibration)
 - Fast events (spikes, metastability)

2c. Classification of ADC Calibration Techniques (1)



- By the domain of the correction:
 - Analog calibration techniques
 - Adjust reference voltages
 - Adjust components (capacitors, resistors)
 - Dynamic matching techniques
 - Digital calibration techniques
 - No adjustment is performed on the analog circuitry
 - Some analog calibration source is always needed
 - (By the nature of the problem any calibration technique is a mixed-mode circuit)

2c. Classification of ADC Calibration Techniques (2)



- By the time the correction is performed:
 - Background calibration techniques
 - Calibration circuits run in parallel and not interfering with the normal functioning of the ADC
 - Off-line calibration techniques
 - Require a specially allocated training mode
 - Offline calibration can be performed
 - At fabrication (expensive, done at testing time)
 - At power-up
 - Periodically (but it incurs inactive times)



End Lecture 12

www.gigalogchip.com